

Notice of References Cited	Application/Control No. 10/707,373		Applicant(s)/Patent Under Reexamination HUISMAN ET AL.	
	Examiner Cynthia Britt		Art Unit 2138	Page 1 of 1

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	V	"Scan Chain Diagnosis Using IDDQ Current Measurement" by Hirase et al. This paper appears in: Eighth Asian Test Symposium, 1999. (ATS '99) Proceedings. Publication Date: 1999 On page(s): 153-157 ISBN: 0-7695-0315-2 INSPEC Accession Number: 6544163
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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